

Product Description

TOP VISUAL High Resolution Semicontact / Noncontact Silicon AFM Cantilevers VIT_P/IR series are specially designed for tip or laser spot precise positioning over the point of interest.

Typical Resonant Frequency 335 kHz (guaranteed range 210–490 kHz), Typical Force Constant 45 N/m (guaranteed range 12–110 N/m).

Cantilevers have Au reflective coating. Probes are also available with no coating as well as with conductive tip coating.

Probes are packed in boxes with 15 and 50 pieces. Amount discount is included in the package price.

General Features

Material	Single Crystal Silicon, N-type, 0.01-0.025 Ohm-cm, Antimony doped
Chip size	3.4x1.6x0.3mm
Reflective side coating	Au
Tip coating	No
Tip curvature radius	typical 6nm, guaranteed 10nm
Available tip coatings	Pt, Au

Special Features

Cantilever series	Cantilever length, L±10µm	Cantilever width, W±5µm	Cantilever thickness, T±1µm	Resonant frequency, kHz			Force constant, N/m		
				min	typical	max	min	typical	max
VIT_P/IR	160	45	4.6	210	335	490	12	45	110